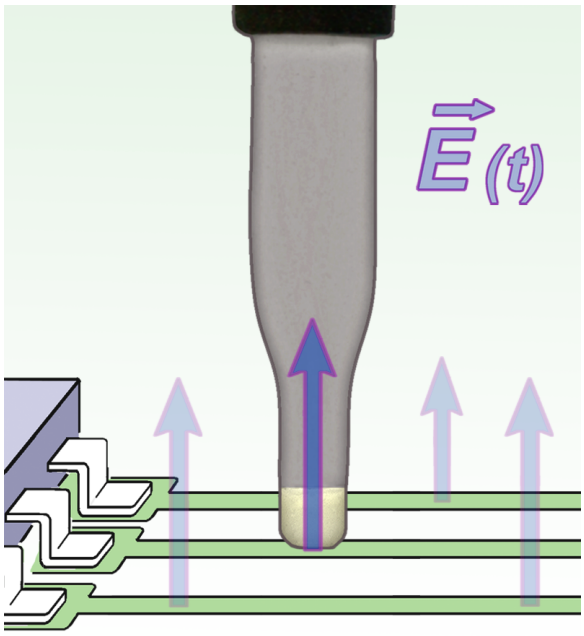
XFS-E 10

Scanner Probe 30 MHz up to 6 GHz



Short description

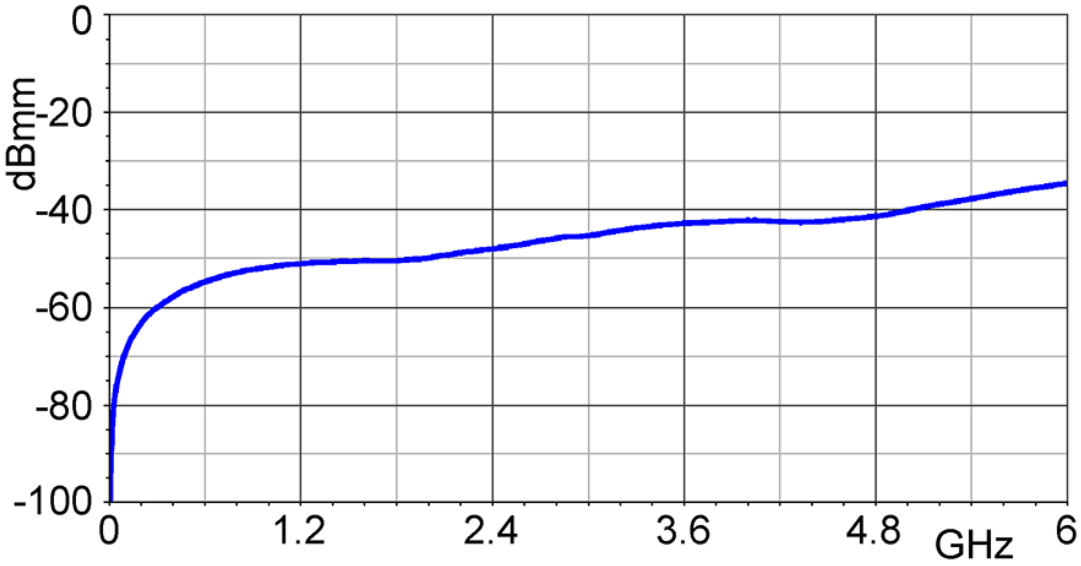
The electrode in the probe head of the XFS-E 10 scanner probe has a width of approx. 0.2 mm. With the probe even smallest E-field sources can be located, e.g. conducting paths with a width of 0.1 mm or single pins on multi pinned ICs. To measure, the E-field probe is positioned onto the object.

The XFS-E 10 probe is a passive near-field probe. Normally the probe head is positioned directly onto the measured object (high electric field strength). It has a current attenuating sheath and, therefore, is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input. The H-field scanner probe has an internal terminating resistance.

Technical parameters

Frequency range	30 MHz ... 6 GHz
Resolution	≈ 0.2 mm
Probe head dimensions	≈ (0.5 x 2) mm
Connector - output	SMA, male, jack

Frequency response [dBµV] / [dBµA/m]

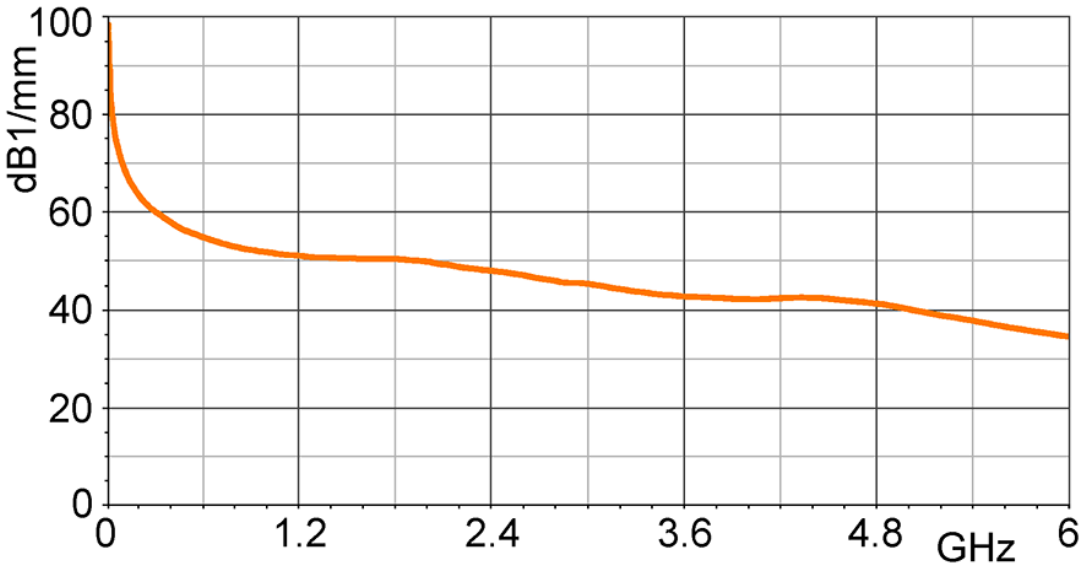


Sales Partner:

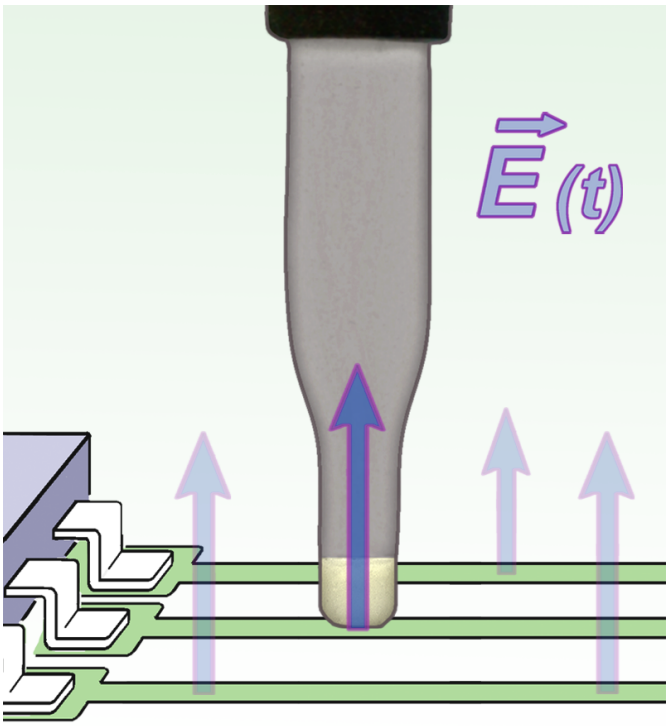
ABSOLUTE EMC Llc.
Covering sales in North America
United States, Mexico, & Canada

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E- field correction curve [dBµV/mm] / [dBµV]



Measuring principles



XFS-E 10

Scanner Probe 30 MHz up to 6 GHz



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